


<b>Search Notes</b>  	<b>Application/Control No.</b>  10519988	<b>Applicant(s)/Patent Under Reexamination</b>  SCHARNWEBER ET AL.
	<b>Examiner</b>  Young J Kim	<b>Art Unit</b>  1637

<b>SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

<b>SEARCH NOTES</b>		
<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
Patent Databases (USPT, USPGP, EPO, JPO, DERWENT, IBM-TDB)	2/27/2008	YJK
see enclosed for text-search strategy	2/27/2008	YJK

<b>INTERFERENCE SEARCH</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>